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(54)	PROBE PIN ASSEMBLY, A METHOD OF MAKING THE SAME AND A CONNECTOR USING THE SAME			
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(58)	Field of So	earch		
(56)	References Cited			
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(57) ABSTRACT

Disclosed are an improved probe pin assembly and a method of making the same. Each probe pin uses a sleeve which is formed by stamping and deep-drawing a thin sheet of metal with dies. The sleeve has a contact pin slidably fitted therein, a resilient member contained therein to spring-bias the contact pin with its tip end appearing from the sleeve and a cover plate fastened to and closing the rear opening of the sleeve.

2 Claims, 4 Drawing Sheets

